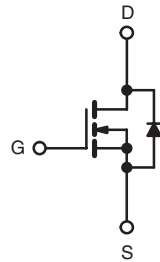
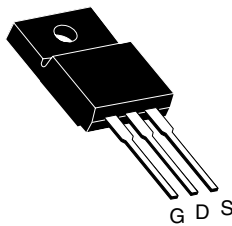


Power MOSFET

PRODUCT SUMMARY		
V_{DS} (V)	500	
$R_{DS(on)}$ (Ω)	$V_{GS} = 10$ V	0.290
Q_g (Max.) (nC)	89	
Q_{gs} (nC)	24	
Q_{gd} (nC)	44	
Configuration	Single	

TO-220 FULLPAK


N-Channel MOSFET

FEATURES

- Low Gate Charge Q_g Results in Simple Drive Requirement
- Improved Gate, Avalanche and Dynamic dV/dt Ruggedness
- Fully Characterized Capacitance and Avalanche Voltage and Current
- Lead (Pb)-free


**RoHS
COMPLIANT**

APPLICATIONS

- Switch Mode Power Supply (SMPS)
- Uninterruptible Power Supply
- High Speed Power Switching

ORDERING INFORMATION	
Package	TO-220 FULLPAK
Lead (Pb)-free	SiHFIB16N50K-E3

ABSOLUTE MAXIMUM RATINGS $T_C = 25$ °C, unless otherwise noted				
PARAMETER	SYMBOL	LIMIT	UNIT	
Drain-Source Voltage	V_{DS}	500	V	
Gate-Source Voltage	V_{GS}	± 30		
Continuous Drain Current ^e	V_{GS} at 10 V	$T_C = 25$ °C	A	
Continuous Drain Current		$T_C = 100$ °C		
Pulsed Drain Current ^a	I_{DM}	27		
Linear Derating Factor		0.36	W/°C	
Single Pulse Avalanche Energy ^b	E_{AS}	290	mJ	
Repetitive Avalanche Current ^a	I_{AR}	6.7	A	
Repetitive Avalanche Energy ^a	E_{AR}	4.5	mJ	
Maximum Power Dissipation	$T_C = 25$ °C	P_D	45	W
Peak Diode Recovery dV/dt^c		dV/dt	24	V/ns
Operating Junction and Storage Temperature Range	T_J, T_{stg}	- 55 to + 150	°C	
Soldering Recommendations (Peak Temperature) ^d	for 10 s			300
Mounting Torque	6-32 or M3 screw		10	lbf · in
			1.1	N · m


Notes

- Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).
- Starting $T_J = 25$ °C, $L = 13$ mH, $R_G = 25$ Ω , $I_{AS} = 6.7$ A, $dV/dt = 17$ V/ns (see fig. 12a).
- $I_{SD} \leq 6.7$ A, $dI/dt \leq 500$ A/ μ s, $V_{DD} \leq V_{DS}$, $T_J \leq 150$ °C.
- 1.6 mm from case.
- Drain current limited by maximum junction temperature.

THERMAL RESISTANCE RATINGS

PARAMETER	SYMBOL	TYP.	MAX.	UNIT
Maximum Junction-to-Ambient	R_{thJA}	-	65	°C/W
Maximum Junction-to-Case (Drain)	R_{thJC}	-	2.76	

SPECIFICATIONS $T_J = 25\text{ }^\circ\text{C}$, unless otherwise noted

PARAMETER	SYMBOL	TEST CONDITIONS	MIN.	TYP.	MAX.	UNIT		
Static								
Drain-Source Breakdown Voltage	V_{DS}	$V_{GS} = 0\text{ V}, I_D = 250\text{ }\mu\text{A}$	500	-	-	V		
V_{DS} Temperature Coefficient	$\Delta V_{DS}/T_J$	Reference to $25\text{ }^\circ\text{C}$, $I_D = 1\text{ mA}$	-	0.59	-	V/°C		
Gate-Source Threshold Voltage	$V_{GS(th)}$	$V_{DS} = V_{GS}, I_D = 250\text{ }\mu\text{A}$	3.0	-	5.0	V		
Gate-Source Leakage	I_{GSS}	$V_{GS} = \pm 30\text{ V}$	-	-	± 100	nA		
Zero Gate Voltage Drain Current	I_{DSS}	$V_{DS} = 500\text{ V}, V_{GS} = 0\text{ V}$	-	-	50	μA		
		$V_{DS} = 400\text{ V}, V_{GS} = 0\text{ V}, T_J = 125\text{ }^\circ\text{C}$	-	-	250			
Drain-Source On-State Resistance	$R_{DS(on)}$	$V_{GS} = 10\text{ V}$ $I_D = 4.0\text{ A}^b$	-	0.290	0.350	Ω		
Forward Transconductance	g_{fs}	$V_{DS} = 50\text{ V}, I_D = 4.0\text{ A}$	4.7	-	-	V		
Dynamic								
Input Capacitance	C_{iss}	$V_{GS} = 0\text{ V}, V_{DS} = 25\text{ V}, f = 1.0\text{ MHz}$	-	2160	-	pF		
Output Capacitance	C_{oss}		-	240	-			
Reverse Transfer Capacitance	C_{rss}		-	27	-			
Output Capacitance	C_{oss}	$V_{GS} = 0\text{ V}$	$V_{DS} = 1.0\text{ V}, f = 1.0\text{ MHz}$	-	2600	-		
			$V_{DS} = 400\text{ V}, f = 1.0\text{ MHz}$	-	62	-		
Effective Output Capacitance	$C_{oss\text{ eff.}}$				$V_{DS} = 0\text{ V to } 400\text{ V}^c$	-	120	-
Total Gate Charge	Q_g	$V_{GS} = 10\text{ V}$	$I_D = 6.7\text{ A}, V_{DS} = 400\text{ V}^b$	-	-	89	nC	
Gate-Source Charge	Q_{gs}			-	-	24		
Gate-Drain Charge	Q_{gd}			-	-	44		
Turn-On Delay Time	$t_{d(on)}$	$V_{DD} = 250\text{ V}, I_D = 6.7\text{ A}$ $R_G = 38\text{ }\Omega, V_{GS} = 10\text{ V}^b$	-	17	-	ns		
Rise Time	t_r		-	16	-			
Turn-Off Delay Time	$t_{d(off)}$		-	28	-			
Fall Time	t_f		-	8.4	-			
Drain-Source Body Diode Characteristics								
Continuous Source-Drain Diode Current	I_S	MOSFET symbol showing the integral reverse p - n junction diode 	-	-	6.7	A		
Pulsed Diode Forward Current ^a	I_{SM}		-	-	27			
Body Diode Voltage	V_{SD}	$T_J = 25\text{ }^\circ\text{C}, I_S = 6.7\text{ A}, V_{GS} = 0\text{ V}^b$	-	-	2.0	V		
Body Diode Reverse Recovery Time	t_{rr}	$T_J = 25\text{ }^\circ\text{C}, I_F = 6.7\text{ A}, di/dt = 100\text{ A}/\mu\text{s}^b$	-	430	640	ns		
Body Diode Reverse Recovery Charge	Q_{rr}		-	2840	4270	nC		
Forward Turn-On Time	t_{on}	Intrinsic turn-on time is negligible (turn-on is dominated by L_S and L_D)						

Notes

- Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).
- Pulse width $\leq 300\text{ }\mu\text{s}$; duty cycle $\leq 2\%$.
- $C_{oss\text{ eff.}}$ is a fixed capacitance that gives the same charging time as C_{oss} while V_{DS} is rising from 0 to 80 % V_{DS} .

TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted

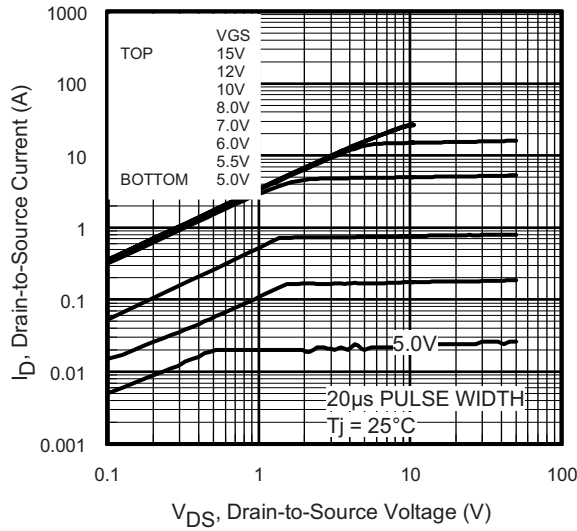


Fig. 1 - Typical Output Characteristics

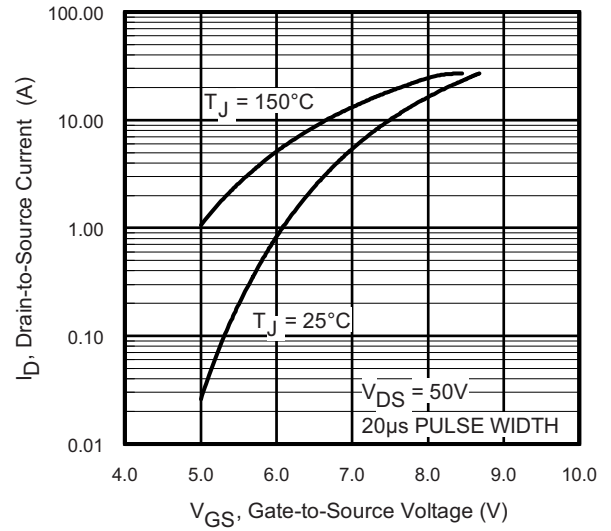


Fig. 3 - Typical Transfer Characteristics

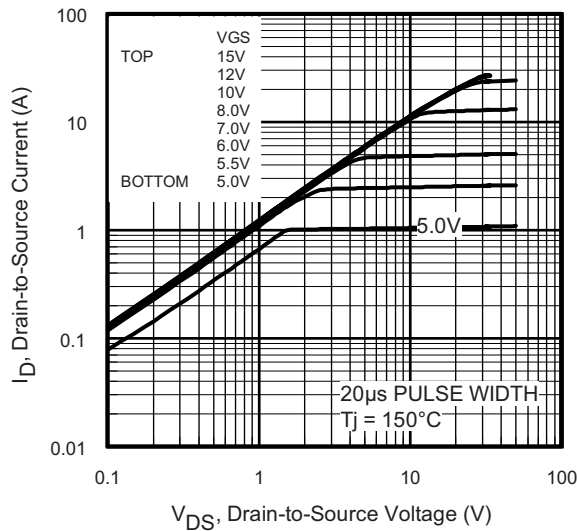


Fig. 2 - Typical Output Characteristics

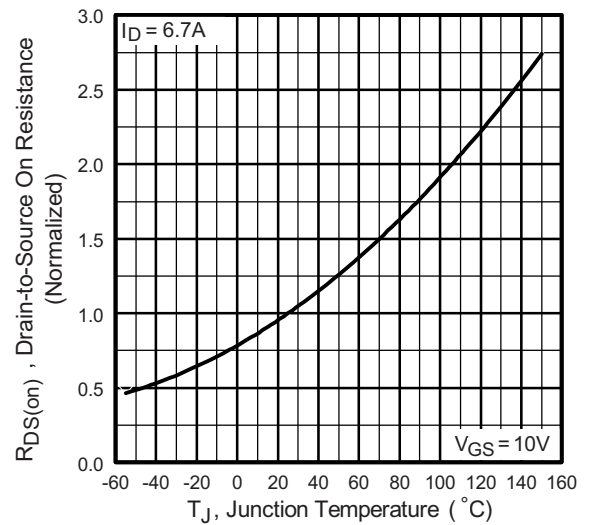


Fig. 4 - Normalized On-Resistance vs. Temperature

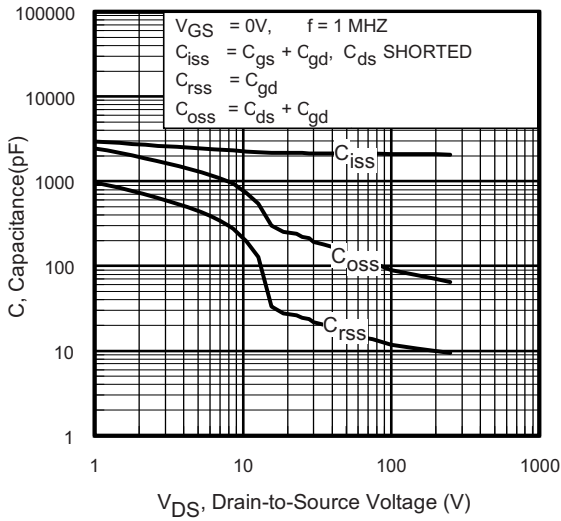


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

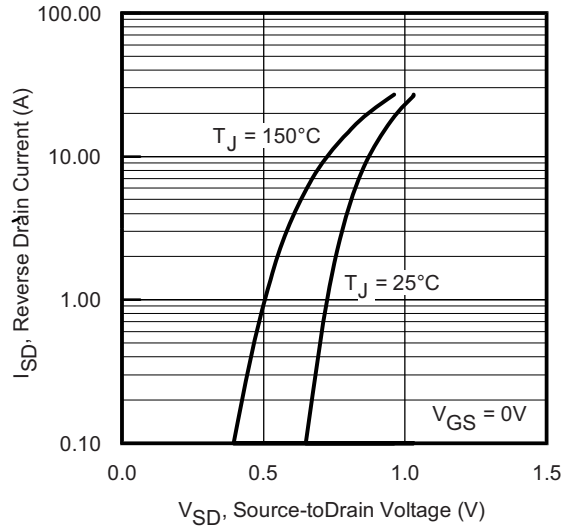


Fig. 7 - Typical Source-Drain Diode Forward Voltage

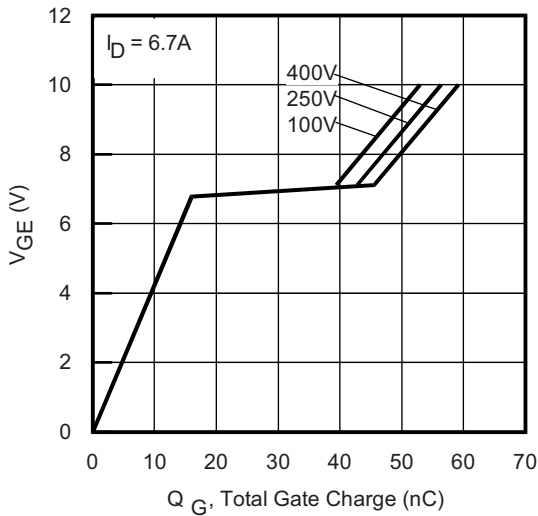


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage

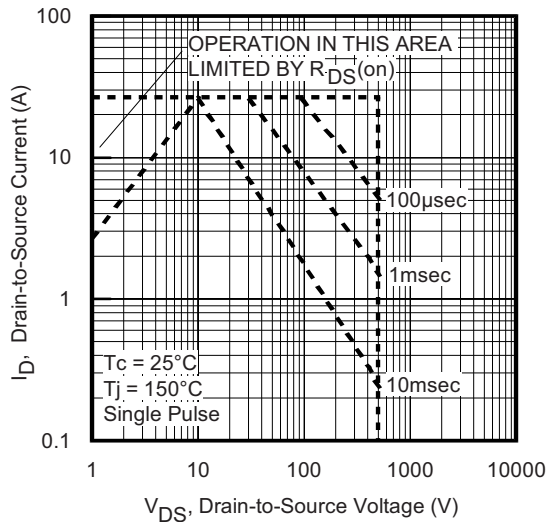


Fig. 8 - Maximum Safe Operating Area

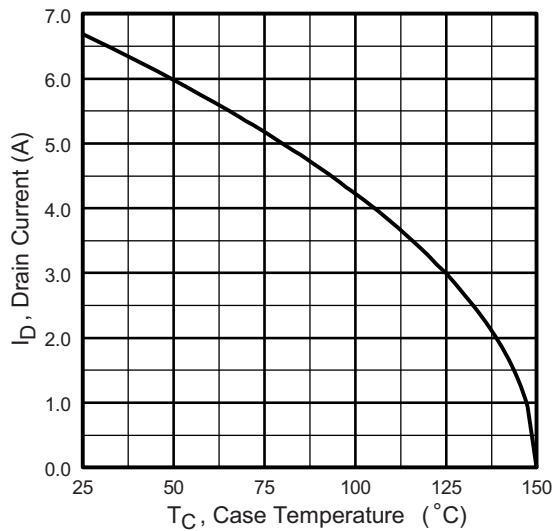


Fig. 9 - Maximum Drain Current vs. Case Temperature

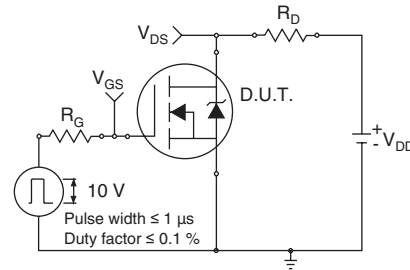


Fig. 10a - Switching Time Test Circuit

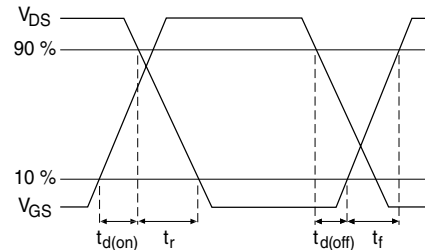


Fig. 10b - Switching Time Waveforms

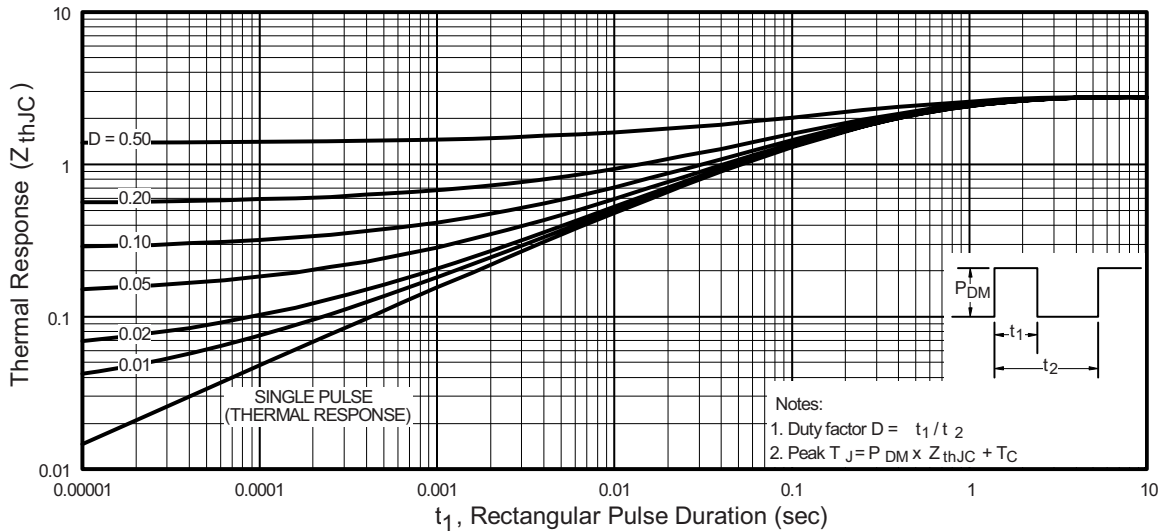


Fig. 11 - Maximum Effective Transient Thermal Impedance, Junction-to-Case

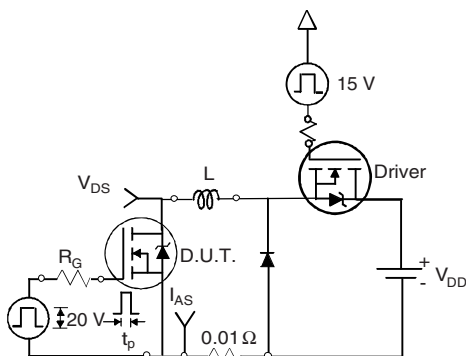


Fig. 12a - Unclamped Inductive Test Circuit

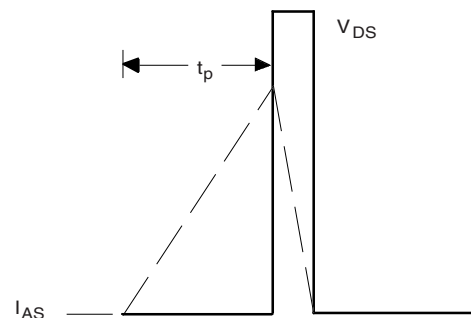


Fig. 12b - Unclamped Inductive Waveforms

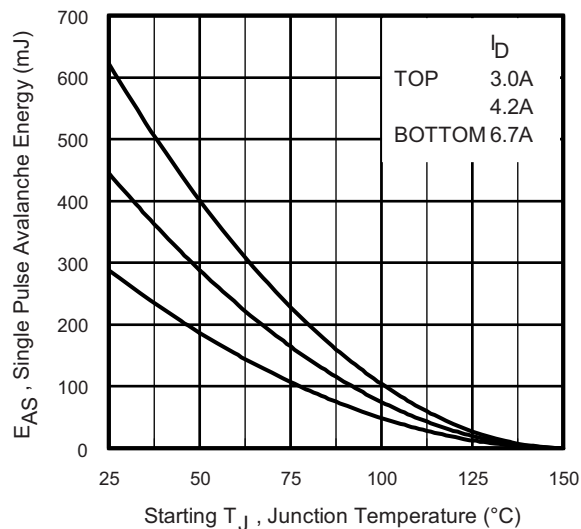


Fig. 12c - Maximum Avalanche Energy vs. Drain Current

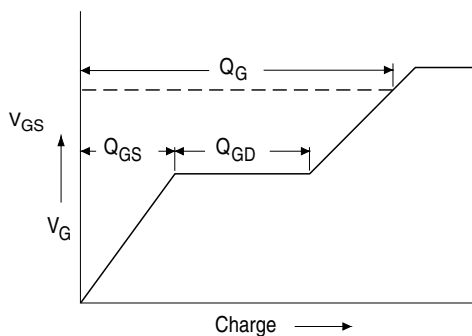


Fig. 13a - Basic Gate Charge Waveform

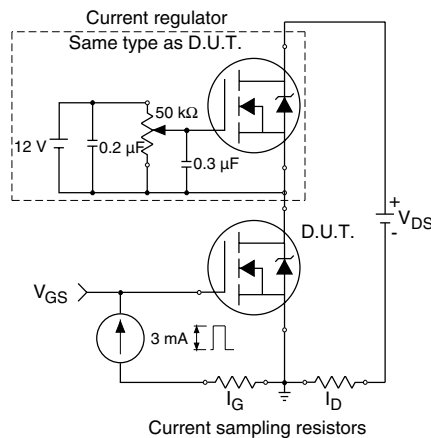
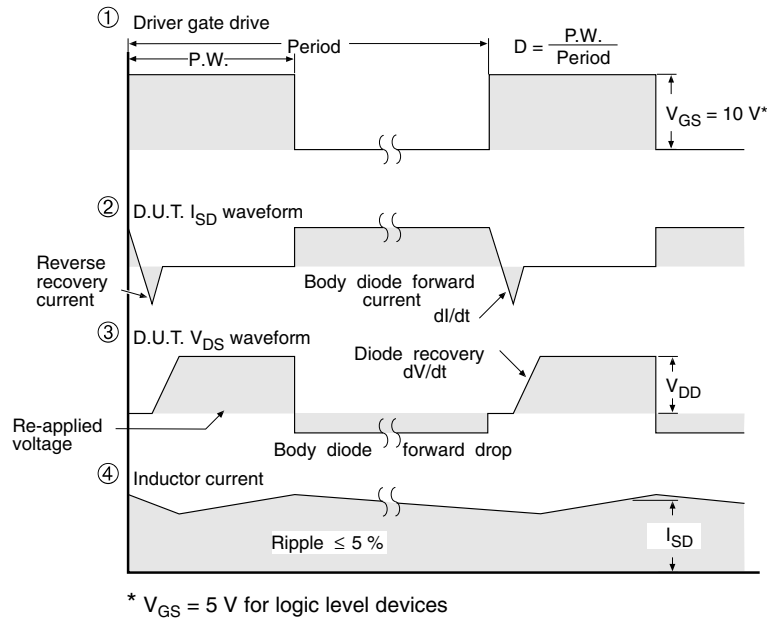
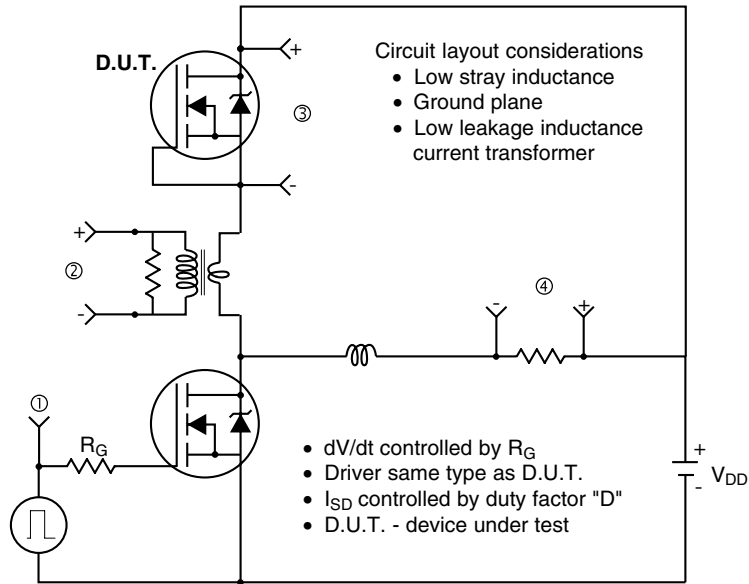


Fig. 13b - Gate Charge Test Circuit

Peak Diode Recovery dV/dt Test Circuit

Fig. 14 - For N-Channel

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